

A scanning electron micrograph (SEM) of a silicon die, likely a microcontroller unit (MCU), showing a grid of square cells. The die is surrounded by a dark border. The grid is composed of thin lines, and the cells contain various patterns, possibly representing individual transistors or memory cells. The text labels are overlaid on the grid.

& Vendor GLOBALFOUNDRIES

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& Metric 1.00

2  $\mu\text{m}$

A horizontal scale bar located at the bottom left of the image, corresponding to the 2 micrometer label.